

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.:	10/701,332	)	
Filed:	November 4, 2003	)	Conf. No.: 5874
Title:	<b>A Novel BISR Mode to Test the Redundant Elements and Regular Functional Memory to Avoid Test Escapes</b>	)	
Inventor:	Ghasi R. Agrawal et al.	)	
Art Unit:	2117	)	
Examiner:	Steve N. Nguyen	)	
Atty. Ref:	03-1343	)	

**RESPONSE TO THE OFFICE ACTION MAILED JULY 17, 2008**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed July 17, 2008, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.